



4/17/2012

**RELIABILITY MONITOR REPORT
FOR**

Fab-7 0.4 μ m Silicon Gate CMOS (S4)

MAXIM Integrated Products

120 San Gabriel Dr.
Sunnyvale, CA 94086

**This Report was prepared by
Maxim Reliability Engineering**

Summary:

The data in the tables that follow was generated as the result of an on-going Process Reliability Monitor. The specific products in this process monitor are:

MAX17114ETM	MAX8790AETP+
-------------	--------------

The calculated failure rate for devices using this process is:

FAILURE RATE: MTTF (YRS): 28098 QUANTITY: 145 FAILS: 0 FITS: 4.1

The parameters used to calculate this failure rate are as follows:

Cf: 60% Ea: 0.7 Tu: 25 °C

The reliability data follows and in this section is the detailed reliability data by stress. The reliability data section includes the latest data available. This report covers data between 4/1/2011 and 3/31/2012 .

Process Information:

Process Description: Fab-7 0.4µm Silicon Gate CMOS (S4)

OPERATING LIFE

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	LOT NO.
HIGH TEMP OP LIFE	1119	MAX17114ETM+	135C	1000 HRS	75	0	FURWCQ002C
HIGH TEMP OP LIFE	1120	MAX8790AETP+	135C	1000 HRS	70	0	FV21C2003C
Total:						0	

STORAGE LIFE

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	LOT NO.
STORAGE LIFE	1119	MAX17114ETM+	150C	1000 HRS	80	0	FURWCQ002C
Total:						0	

TEMPERATURE CYCLE

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	LOT NO.
TEMP CYCLE, 5' RAMP, 10' DWELL	1119	MAX17114ETM+	-65C TO 150C	500 CYS	80	0	FURWCQ002C
Total:						0	

FAILURE RATE: MTTF (YRS): 28098 QUANTITY: 145 FAILS: 0 FITS: 4.1